

Application/Control No.	Applicant(s)/Patent under Reexamination
09/647,786	HAYAKAWA ET AL.
Examiner	Art Unit
JYOTHSNA A. VENKAT Ph. D	1615

SEARCHED						
Class	Subclass	Date	Examiner			
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424	465					
	464					
	474					

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NOTES					
(INCLUDING SEARCH STRATEGY)					
	DATE,	EXMR			
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